

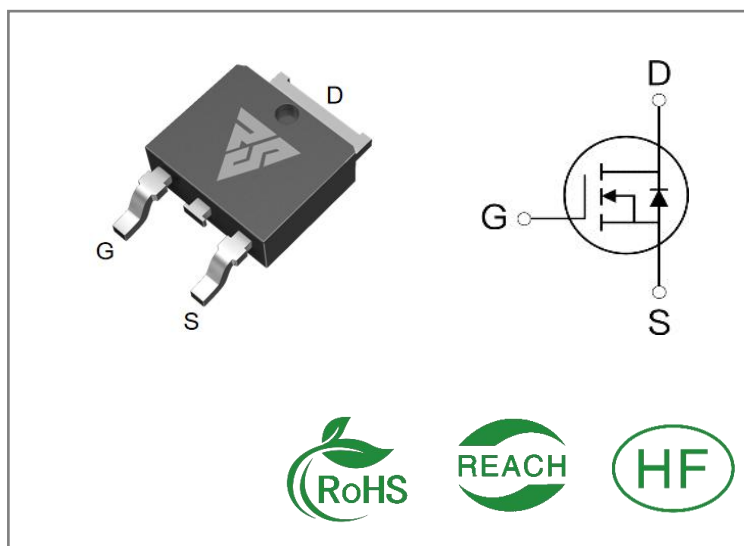
ID	$R_{DS(ON)}$ (Typ)	VDSS
120A	2.8mΩ	40V

**Applications:**

- Load Switch
- PWM Applications
- Power Managment

**Features:**

- Fast switching speed
- 100% avalanche tested
- Improved dv/dt capability


**Ordering Information**

Part Number	Package	Marking	Packing	Qty.
RS40N120D	T0-252	RS40N120D	Tape&reel	2500 PCS

**Absolute Maximun Ratings**  $T_c = 25^{\circ}\text{C}$  unless otherwise specified

Symbol	Parameter	RS40N120D	Units
VDSS	Drain-to-Source Voltage	40	V
ID	Continuous Drain Current $T_C=25^{\circ}\text{C}$	120	A
ID	Continuous Drain Current $T_C=100^{\circ}\text{C}$	76	
IDM	Pulsed Drain Current	390	
PD	Power Dissipation	110	W
VGS	Gate- to- Source Voltage	$\pm 20$	V
EAS	Single Pulse Avalanche Engergy $L = 0.5\text{mH}, V_{DD} = 40\text{V}, V_G = 10\text{V}, T_j = 25^{\circ}\text{C}$	272	mJ
TL TPKG	Maximum Temperature for Soldering	300 260	$^{\circ}\text{C}$
	Leads at 0.063in(1.6mm)from Case for 10 seconds Package Body for 10 seconds		
TJ and TSTG	Operating Junction and Storage Temperature Range	-55 to 150	

\* Drain Current Limited by Maximum Junction Temperature

Caution: Stresses greater than those listed in the“ Absolute Maximum Ratings” Table may cause permanent damage to the device.

**Thermal Resistance**

Symbol	Parameter	RS40N120D	Units	Test Conditions
R $\theta$ JC	Junction-to-Case	1.14	°C / W	Drain lead soldered to water cooled heatsink, PD adjusted for a peak junction temperature of + 150 °C
R $\theta$ JA	Junction-to-Ambient	20		1 cubic foot chamber, free air.

**OFF Characteristics** TJ= 25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BVDSS	Drain- to- source Breakdown Voltage	40	--	--	V	VGS=0V, ID=250 $\mu$ A
IDSS	Drain- to- Source Leakage Current	--	--	1	$\mu$ A	VDS=40V, VGS=0V
IGSS	Gate- to- Source Forward Leakage	--	--	100	nA	VGS=20V , VDS=0V
	Gate- to- Source Reverse Leakage	--	--	-100		VGS=-20V , VDS=0 V

**ON Characteristics** TJ=25°C unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
RDS(on)	Static Drain- to- Source On-Resistance	--	2.8	3.5	m $\Omega$	VGS=10V, ID=15A
		--	4.0	4.8	m $\Omega$	VGS=4.5V, ID=10A
VGS(TH)	Gate Threshold Voltage	1.0	--	2.5	V	VGS=VDS, ID=250 $\mu$ A

**Resistive Switching Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
td(ON)	Turn- on Delay Time	--	12	--	nS	VDS=20V ID=20A RG=3 $\Omega$
trise	Rise Time	--	54	--		
td(OFF)	Turn- OFF Delay Time	--	120	--		
tfall	Fall Time	--	80	--		

**Dynamic Characteristics** Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
Ciss	Input Capacitance	--	4645	--	pF	VGS= 0V VDS=20V f=1.0MHz
Coss	Output Capacitance	--	436	--		
Crss	Reverse Transfer Capacitance	--	360	--		
Qg	Total Gate Charge	--	102	--	nC	VDS= 20V ID=20A VGS=10V
Qgs	Gate- to- Source Charge	--	15.8	--		
Qgd	Gate-to-Drain(" Miller") Charge	--	21.9	--		

**Source- Drain Diode Characteristics**

Symbol	Parameter	Min.	Typ.	Max.	Units	Test Conditions
IS	Continuous Source Current	--	--	120	A	Integral pn- diode in MOSFET
ISM	Maximum Pulsed Current	--	--	390	A	
VSD	Diode Forward Voltage	--	--	1.2	V	IS=15A,VGS=0V
trr	Reverse Recovery Time	--	22.3	--	nS	VGS=0V IS=20A di/dt=100A/μs
Qrr	Reverse Recovery Charge	--	7.4	--	nC	

**Notes:**

- \* 1. Repetitive rating,pulse width limited by maximum junction temperature.
- \* 2. Pulse Test: Pulse width ≤ 300μs, Duty Cycle ≤ 1%

**Typical Feature Curve**

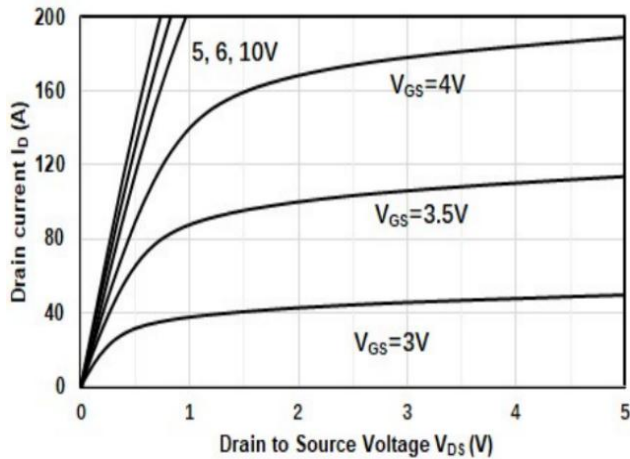


Figure1. Output Characteristics

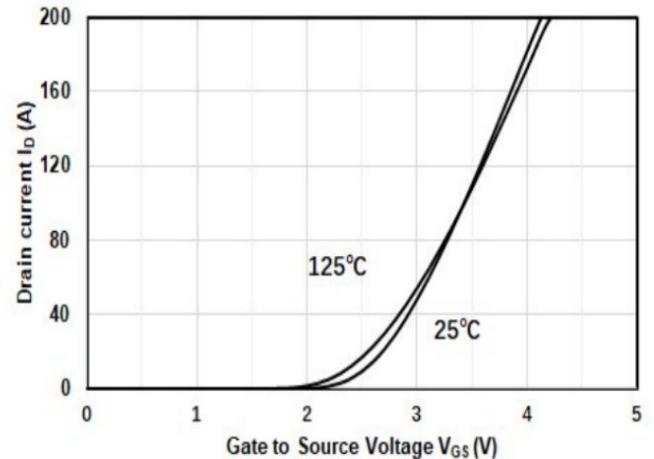


Figure2. Transfer Characteristics

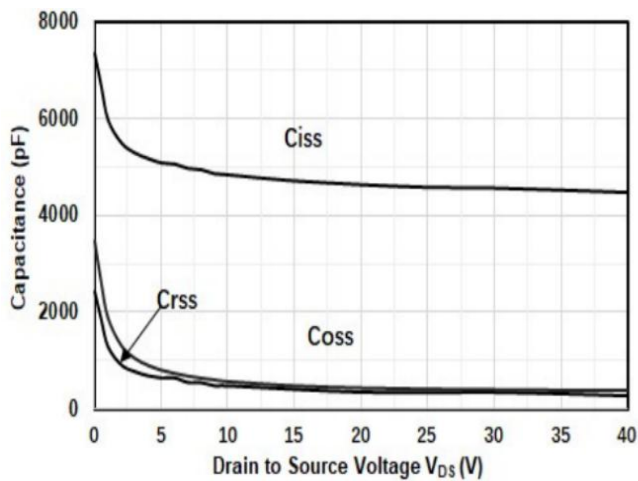


Figure3. Capacitance Characteristics

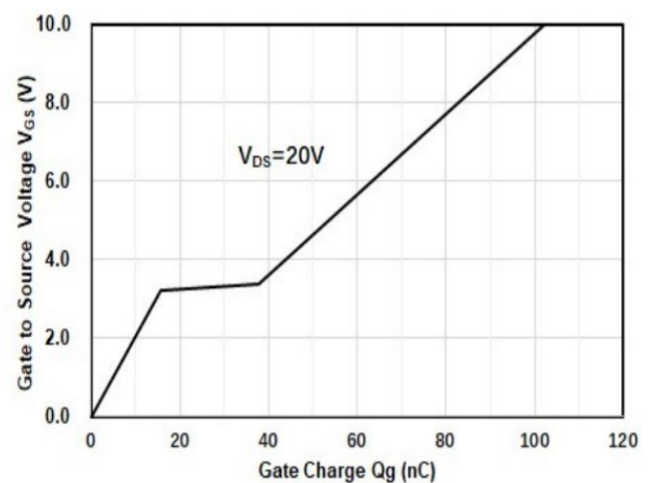


Figure4. Gate Charge

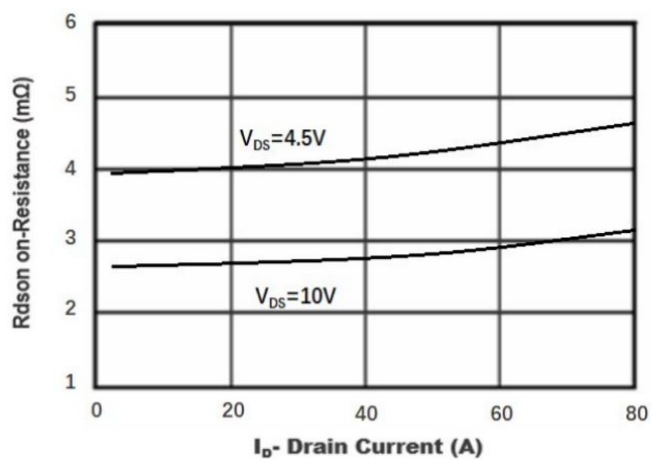


Figure5. Drain-Source on Resistance

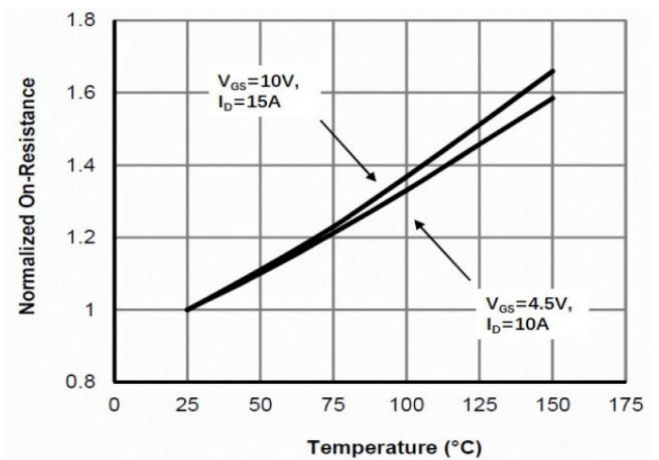


Figure6. Drain-Source on Resistance

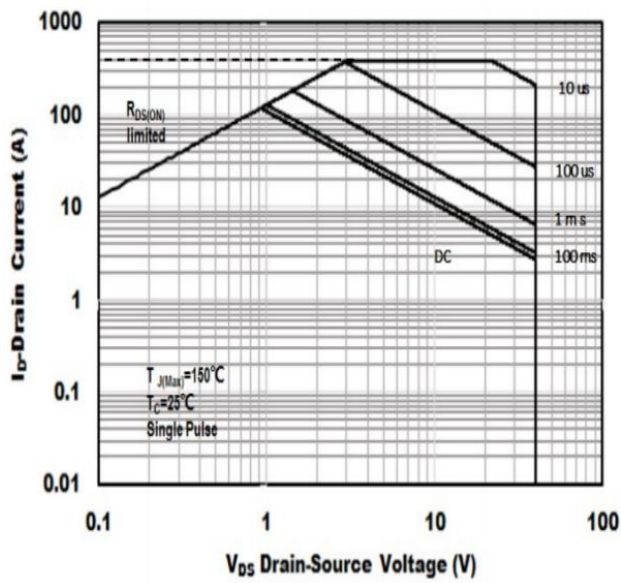


Figure7. Safe Operation Area

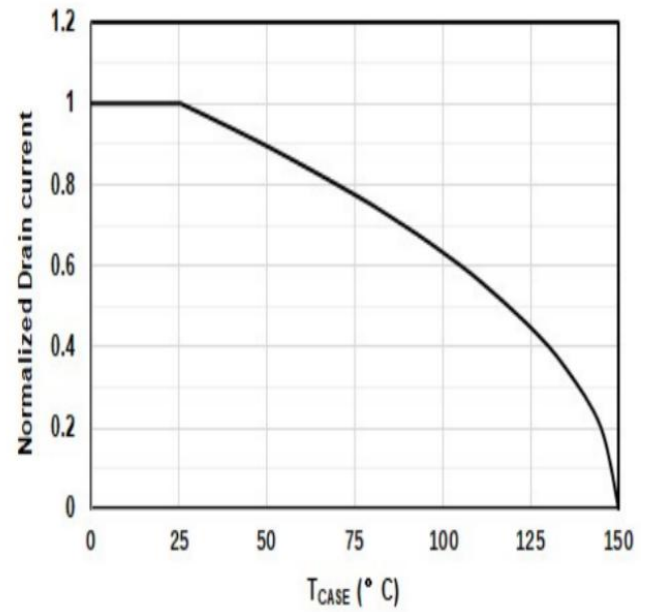


Figure8. Drain current vs. Case Temperature

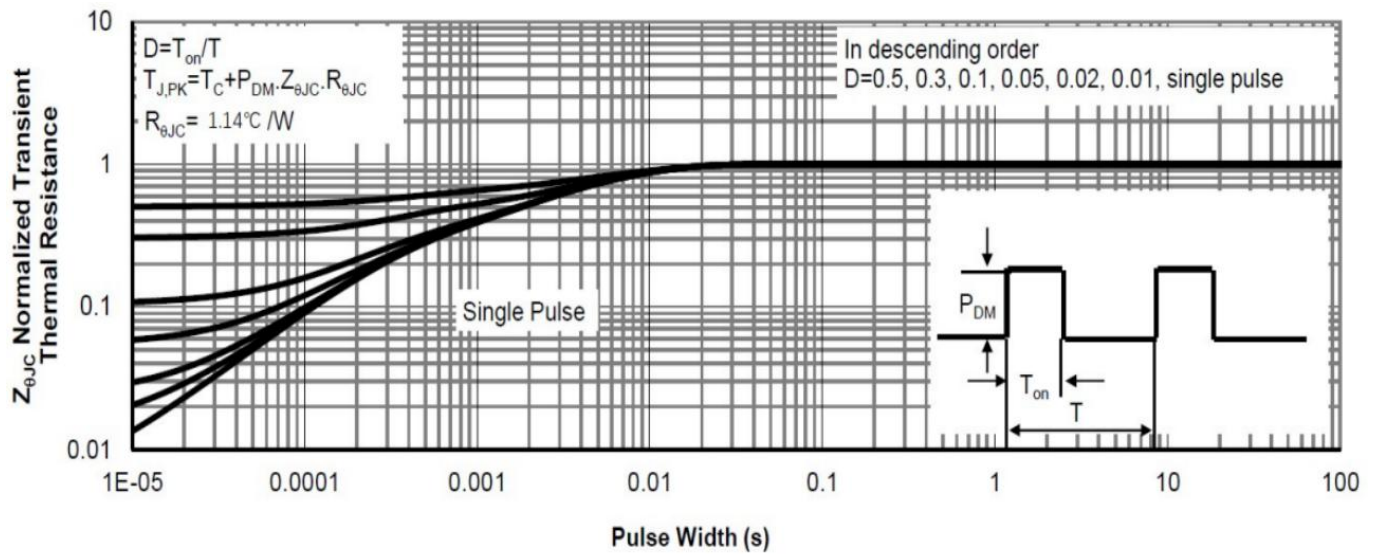


Figure9. Normalized Maximum Transient Thermal Impedance

**Test Circuits and Waveforms**

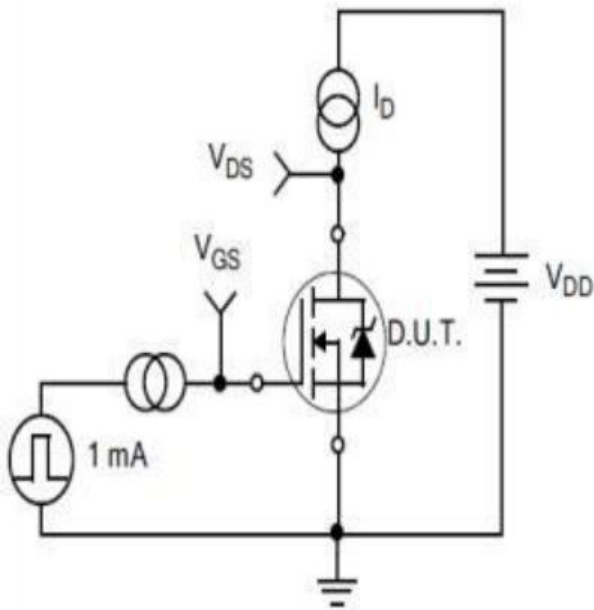


Figure A.  
Gate Charge Test Circuit

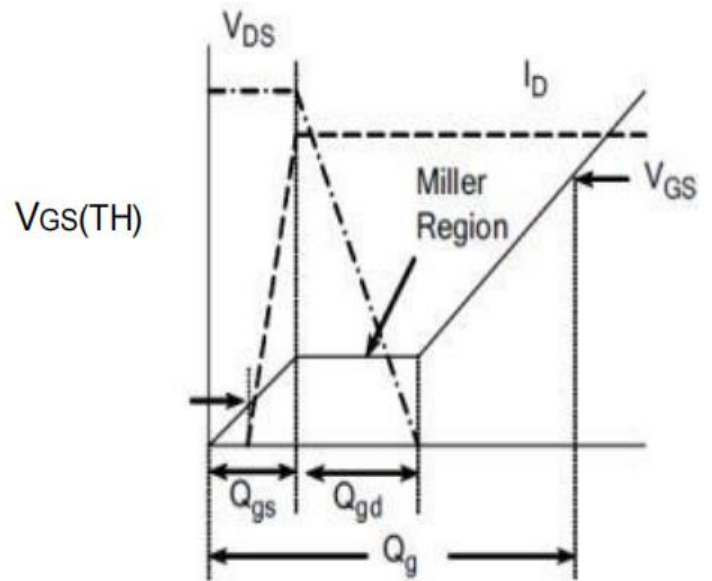


Figure B.  
Gate Charge Waveform

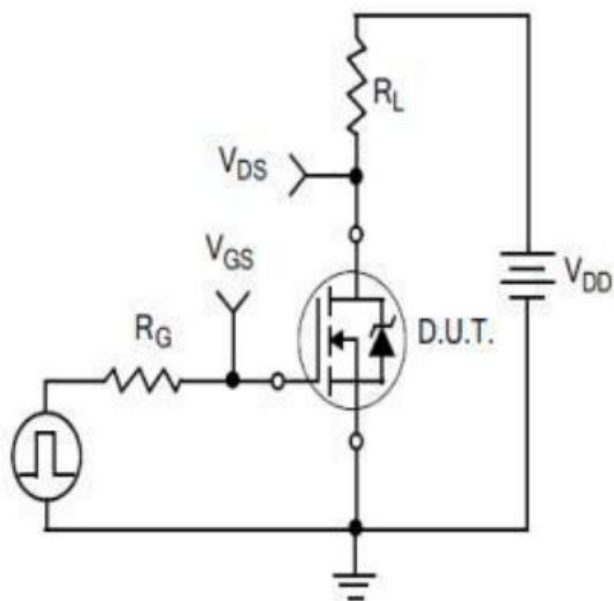


Figure C.  
Resistive Switching Test Circuit

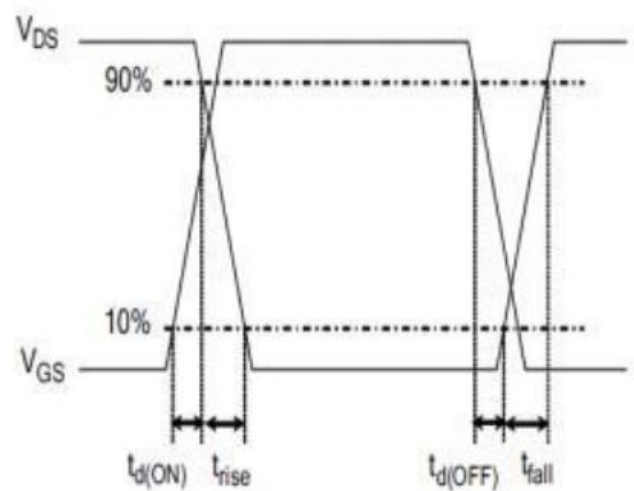


Figure D.  
Resistive Switching Waveforms

# Test ircuits and Waveforms

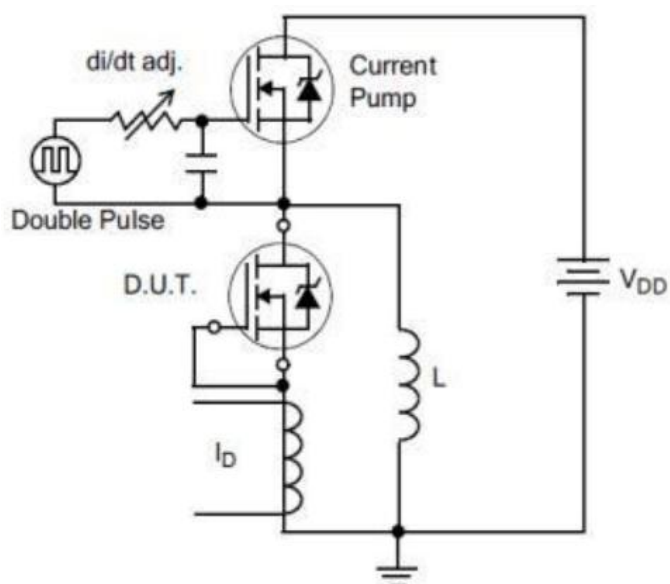


Figure E. Diode Reverse Recovery Test Circuit

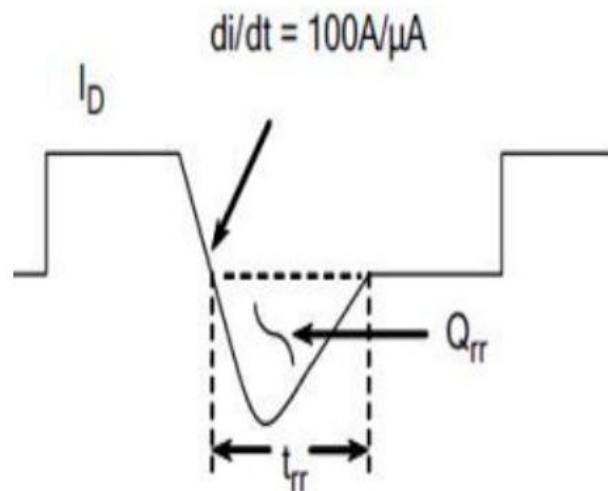


Figure F. Diode Reverse Recovery Waveform

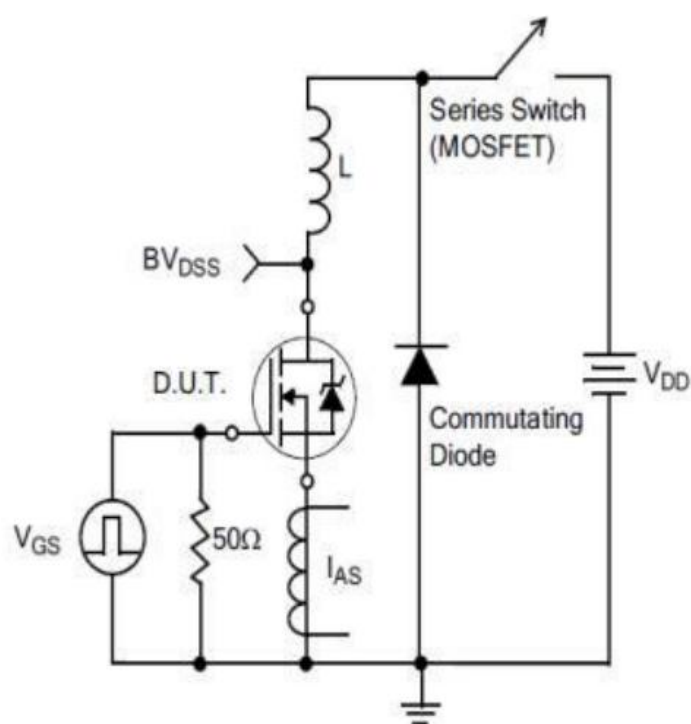
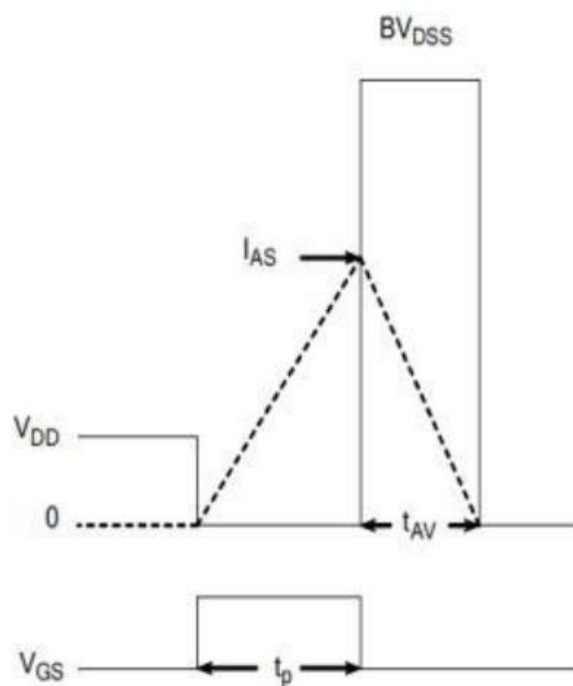


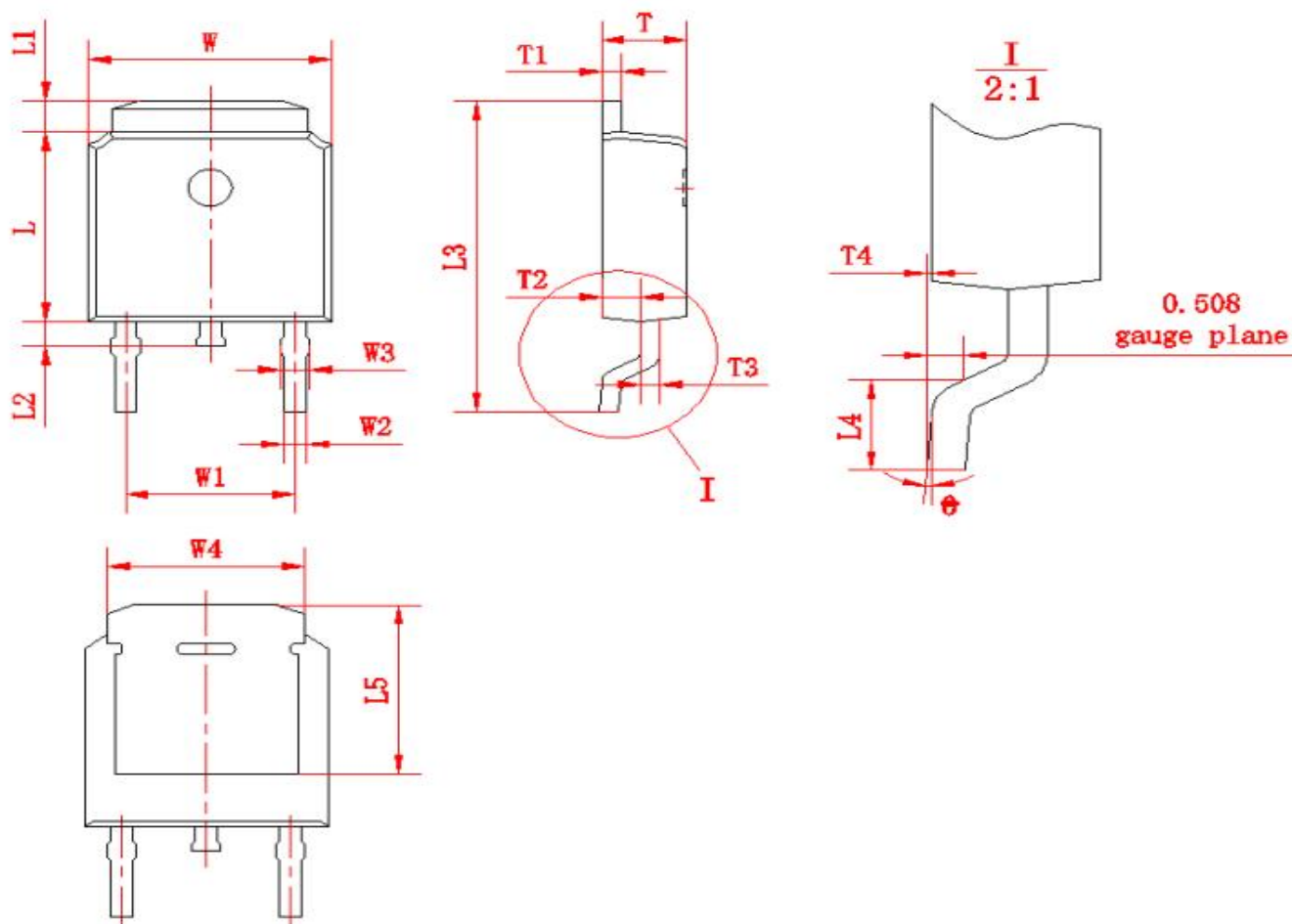
Figure G. Unclamped Inductive Switching Test Circuit



$$EAS = \frac{I_{AS}^2 L}{2}$$

Figure H. Unclamped Inductive Switching Waveforms

**Package outline drawing(TO-252 Unit: mm )**



符号	尺寸		符号	尺寸		符号	尺寸	
	Min	Max		Min	Max		Min	Max
W	6.50	6.70	L1	0.80	1.20	T1	0.48	0.58
W1	(4.572)		L2	0.60	1.00	T2	0.95	1.15
W2	0.6	0.8	L3	9.70	10.30	T3	0.48	0.58
W3	0.68	0.88	L4	1.30	1.70	T4	0.00	0.12
W4	(5.3)		L5	(5.20)		0	0	8
L	6.00	6.20	T	2.20	2.40			

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